

<b>Notice of References Cited</b>	Application/Control No. 10/776,006		Applicant(s)/Patent Under Reexamination YACH ET AL.	
	Examiner Jared M. Bibbee		Art Unit 2161	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0029214 A1	03-2002	Yianilos et al.	707/7
*	B	US-2002/0059299 A1	05-2002	Spaey, Frederic	707/104.1
*	C	US-6,286,032 B1	09-2001	Oberlander et al.	709/203
*	D	US-2004/0025072 A1	02-2004	Mau, Louis S.	713/400
*	E	US-5,684,990	11-1997	Boothby, David J.	707/203
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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